

033082M298



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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Tsuneyuki OKABE, et al.

U.S. Serial No.: 10/564,558

Group Art Unit: 2812

Filed: : January 13, 2006

Examiner: To Be Assigned

For: SEMICONDUCTOR MANUFACTURING APPARATUS AND  
SEMICONDUCTOR MANUFACTURING METHOD

**THIRD INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

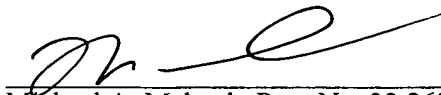
Pursuant to the duty of disclosure under 37 C.F.R. 1.56, Applicants are enclosing an Information Disclosure Citation Form (PTO-1449) which lists the references cited in the attached Japanese Office Action dated July 11, 2006. An English translation of the noted portions of the Japanese Office Action is enclosed.

Applicants certify under 37 C.F.R. 1.97(e)(1) that all documents submitted herewith were cited in a communication from a foreign patent office in a counterpart foreign application no more than three months prior to the filing of this Statement. Therefore, it is respectfully urged that no fees are required for the Examiner's consideration of the documents listed in this Information Disclosure Statement.

It is respectfully requested that the cited documents be considered by the Examiner in the above-identified patent application and that the cited documents be made officially of record therein. It is further requested that a listing of the same appear on the face of any patent which may issue from this application.

Respectfully submitted,  
SMITH, GAMBRELL & RUSSELL, LLP

By:

  
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August 10, 2006



FORM PTO-1449  INFORMATION DISCLOSURE STATEMENT	ATTY. DOCKET 033082M298	SERIAL NO. 10/564,558
	APPLICANT: Tsuneyuki OKABE, et al.	
	FILING DATE January 13, 2006	GROUP ART UNIT 2812

### U.S. PATENT DOCUMENTS

*Examiner's Initials		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE, IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						

### FOREIGN PATENT DOCUMENTS

*Examiner's Initials		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO	
	AH	09-184600	7/15/97	Japan			X	
	AI							
	AJ							
	AK							
	AL							
	AM							
	AN							
	AO							
	AP							

### OTHER INFORMATION (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	
	AR	
	AS	
EXAMINER:		DATE CONSIDERED:
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		